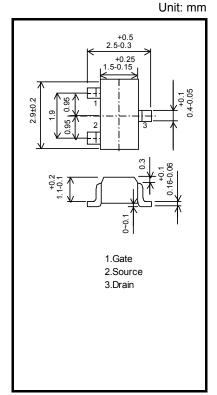


# **High Speed Switching Applications** Analog Switch Applications

- Small package
- Low on resistance
  - $: R_{on} = 4.0 \Omega (max) (@V_{GS} = 4 V)$

## Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V <sub>DS</sub>	30	V	
Gate-source voltage		V <sub>GSS</sub>	±20	V	
Drain current	DC	I <sub>D</sub>	100	mA	
	Pulse	I <sub>DP</sub>	200	ШA	
Drain power dissipation (Ta = $25^{\circ}$ C)		PD	200	mW	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature		T <sub>stg</sub>	-55~150	°C	



Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the

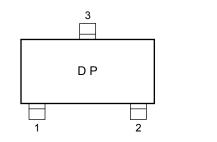
Weight: 0.012 g (typ.)

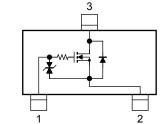
reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the TY Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

## Marking

# **Equivalent Circuit**





## **Handling Precaution**

When handling individual devices (which are not yet mounting on a circuit board), be sure that the environment is protected against electrostatic electricity. Operators should wear anti-static clothing, and containers and other objects that come into direct contact with devices should be made of anti-static materials.

TY Semicondutor<sup>®</sup>

- $: R_{on} = 7.0 \Omega (max) (@V_{GS} = 2.5 V)$



# SSM3K15F

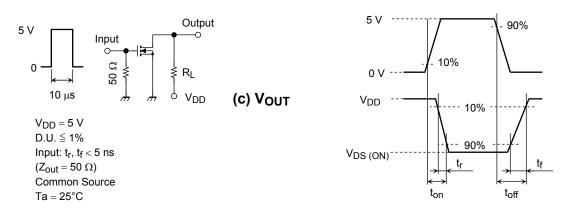
### **Electrical Characteristics (Ta = 25°C)**

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	$V_{GS}=\pm 16~V,~V_{DS}=0$	_		±1	μA
Drain-source breakdown voltage		V (BR) DSS	$I_D = 0.1 \text{ mA}, V_{GS} = 0$	30	_	_	V
Drain cut-off curre	ent	I <sub>DSS</sub>	$V_{DS} = 30 V, V_{GS} = 0$	_		1	μA
Gate threshold vo	Itage	V <sub>th</sub>	$V_{DS} = 3 V, I_D = 0.1 mA$	0.8		1.5	V
Forward transfer a	admittance	Y <sub>fs</sub>	$V_{DS} = 3 V, I_D = 10 mA$	25			mS
Drain-source ON resistance		R <sub>DS (ON)</sub>	$I_D = 10 \text{ mA}, V_{GS} = 4 \text{ V}$	_	2.2	4.0	Ω
			$I_D = 10 \text{ mA}, V_{GS} = 2.5 \text{ V}$	_	4.0	7.0	
Input capacitance		C <sub>iss</sub>	$V_{DS} = 3 V, V_{GS} = 0, f = 1 MHz$	_	7.8		pF
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = 3 V, V_{GS} = 0, f = 1 MHz$	_	3.6		pF
Output capacitance		C <sub>oss</sub>	$V_{DS} = 3 V, V_{GS} = 0, f = 1 MHz$	_	8.8		pF
Switching time	Turn-on time	t <sub>on</sub>	V <sub>DD</sub> = 5 V, I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0~5 V	—	50	—	ns
	Turn-off time	t <sub>off</sub>		_	180	—	

## Switching Time Test Circuit

#### (a) Test circuit

(b) V<sub>IN</sub>



### Precaution

 $V_{th}$  can be expressed as voltage between gate and source when low operating current value is  $I_D$  = 100  $\mu A$  for this product. For normal switching operation,  $V_{GS}$  (on) requires higher voltage than  $V_{th}$  and  $V_{GS}$  (off) requires lower voltage than  $V_{th}$ .

(relationship can be established as follows:  $V_{GS}$  (off) <  $V_{th}$  <  $V_{GS}$  (on) )

Please take this into consideration for using the device.